


<b>Search Notes</b>  	<b>Application/Control No.</b>  10020585	<b>Applicant(s)/Patent Under Reexamination</b>  SAKATANI, NOBUYOSHI
	<b>Examiner</b>  Bruckart, Benjamin R	<b>Art Unit</b>  2155

SEARCHED			
Class	Subclass	Date	Examiner
709	203, 224, 223, 245	9/18/06	bb
705	14	9/18/06	bb
709	203, 217, 224, 227	2/8/07	brb
705	14	2/8/07	brb
709	217	7/11/07	brb

SEARCH NOTES		
Search Notes	Date	Examiner
Searched East (USPat, USPG_Pub, JPO, EPO, Derwent). Considered for allowance but spoke with S. Najjar, J. Cardone, Eric Stamber, and John Hayes.	9/18/06	bb
Searched East (USPat, USPG_Pub) keyword, date, class search but focused on arguments	2/8/07	bb
Text search of East (USPat, USPG_Pub, JPO, EPO, Derwent, IBM_TDB) see search history	7/11/07	brb
Limited classification search of 709/203, 224, 227 and 705/14. Inventor and Foreign Search	7/11/07	brb
STIC template search	7/11/07	brb

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
709	217	7/11/07	brb